FEI Quanta 200
The Ultimate low-vacuum SEM with extended low-vacuum capabilities for the really challenging samples and dynamic experiments

Technologies, materials and samples are changing faster than ever before, and so are the requirements of today’s analytical laboratory. Analytical tools need to accommodate materials with very different properties while collecting more analytical data in less time. The demand for non-destructive analytical techniques and functionality is increasing.

The Quanta™ series from FEI is the advanced, flexible solution for current and future diagnostics applications. Featuring three imaging modes – high-vacuum, low-vacuum and ESEM™ it accommodates the widest range of samples of any SEM system. It is engineered to provide maximum data – imaging and microanalysis – from all specimens, with or without preparation.

The new 2nd generation of Quanta’s feature improved image resolution and contrast thanks to a new imaging engine that also accommodates remote control.

The Quanta series delivers more value for your investment.

- Increase your imaging capabilities with high resolution high-, low- and extended low-vacuum (ESEM) secondary electron imaging
- Minimize switching between different detectors, have all the information from the different detectors instantly available on one single screen in Quanta’s four Quadrant user interface
- Minimize the amount of sample preparation, low- and ESEM-vacuum capability enables charge free imaging and analysis of non-conductive specimens and/or hydrated specimens
- Increase your analysis capabilities by performing in-situ dynamic experiments and live record them on video
- Increase your analytical capabilities by enabling EDS analysis on non-conductive samples in low-vacuum thanks to Quanta’s patented through the lens pumping
- Increase your flexibility and operate the microscope from any computer by using Quanta’s remote capability
- Minimal requirements on floor space, power supply and environment
Essential specs

Electron optics
• High-performance thermal emission-SEM column with dual-anode source emission geometry, fixed objective aperture and through-the-lens differential pumping
• Filament lifetime > 100 hours

Vacuum system
• 1x 240 l/s TMP, 1x PVP
• Patented through-the-lens differential pumping
• Beam gas path length: 10 or 2 mm

Chamber vacuum
• High-vacuum: < 6e-4 Pa
• Low-vacuum: 10 to 130 Pa
• ESEM-vacuum: 10 to 2600 Pa

Resolution
• High-vacuum
  - 3.0nm at 30kV (SE)
  - 4.0nm at 30kV (BSE)
  - 10nm at 3kV (SE)
• Low-vacuum
  - 3.0nm at 30kV (SE)
  - 4.0nm at 30kV (BSE)
  - < 12nm at 3kV (SE)
• Extended vacuum mode (ESEM)
  - 3.0nm at 30kV (SE)
• Accelerating voltage: 200V – 30kV
• Probe current: up to 2µA – continuously adjustable

Chamber
• 284mm left to right
• 10mm analytical WD
• 8 ports
• EDX take-off angle: 35°

4-axis motorized stage
• Eucentric goniometer stage
• X,Y = 50mm
• Z = 50mm (25mm motorised)
• T = -15° to +75° (manual)
• R = 360° continuous
• Repeatability: 2µm

Detectors
• Everhardt-Thornley SED
• Low-vacuum SED (LFD)
• Gaseous SED (GSED)
• IR-CCD
• Solid-state BSED
• Gaseous analytical BSED (GAD)*
• Scintillator BSED/CLD*
• Gaseous BSED*
  * optional

System control
• 32-bit graphical user interface with Windows XP, keyboard, optical mouse
• Image display: 19-inch LCD, SVGA 1280 x 1024
• Single frame or 4-quadrant image display
• 4-quadrant live

Image processor
• Up to 4096 x 3536 pixels
• File type: TIFF (8- or 16-bit), BMP or JPEG

Installation requirements
• Power: voltage 230V (+6%, -10%)
• Frequency: 50 or 60 Hz (+/- 1%)
• Power consumption: < 2.0kVA for basic microscope
• Environment:
  - temperature 15-30°C
  - relative humidity below 80% RH
  - stray AC magnetic fields
  - 100mT asynchronous
  - 300mT synchronous
• Door width: 90cm
• Weight: column console 450kg
• No compressed air or water cooling is required

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